



Institute of Electrical Engineering SAS

Eugen SEILER, Rastislav RIES

SC characterization at IEE Bratislava

IEE OVERVIEW

Sample Batches since the last meeting (Sept.):

prepared at Siegen Uni:

- HiPIMS Nb films on Cu – 4.9.2020 series
6.10.2020 series *meas. in progress...*

prepared at STFC:

- HiPIMS Nb on Cu – 22.7.2020 series
- V_3Si , HiPIMS Nb, NbTiN, var. substrates (Cu, Sapp, Ta, vitr.C) – 18.9.2020 series
not measured yet...

Unexpected Outage – PPMS down 15.10.-12.11.

ARIES measurements resumed 30.11.

Article on Laser treated Nb samples (*R. Ries*)

Significant changes (more material characterisation), submitted to Applied Surface Science (27.11.)

COVID-19 related restrictions at IEE – mild so far...

Table-summary

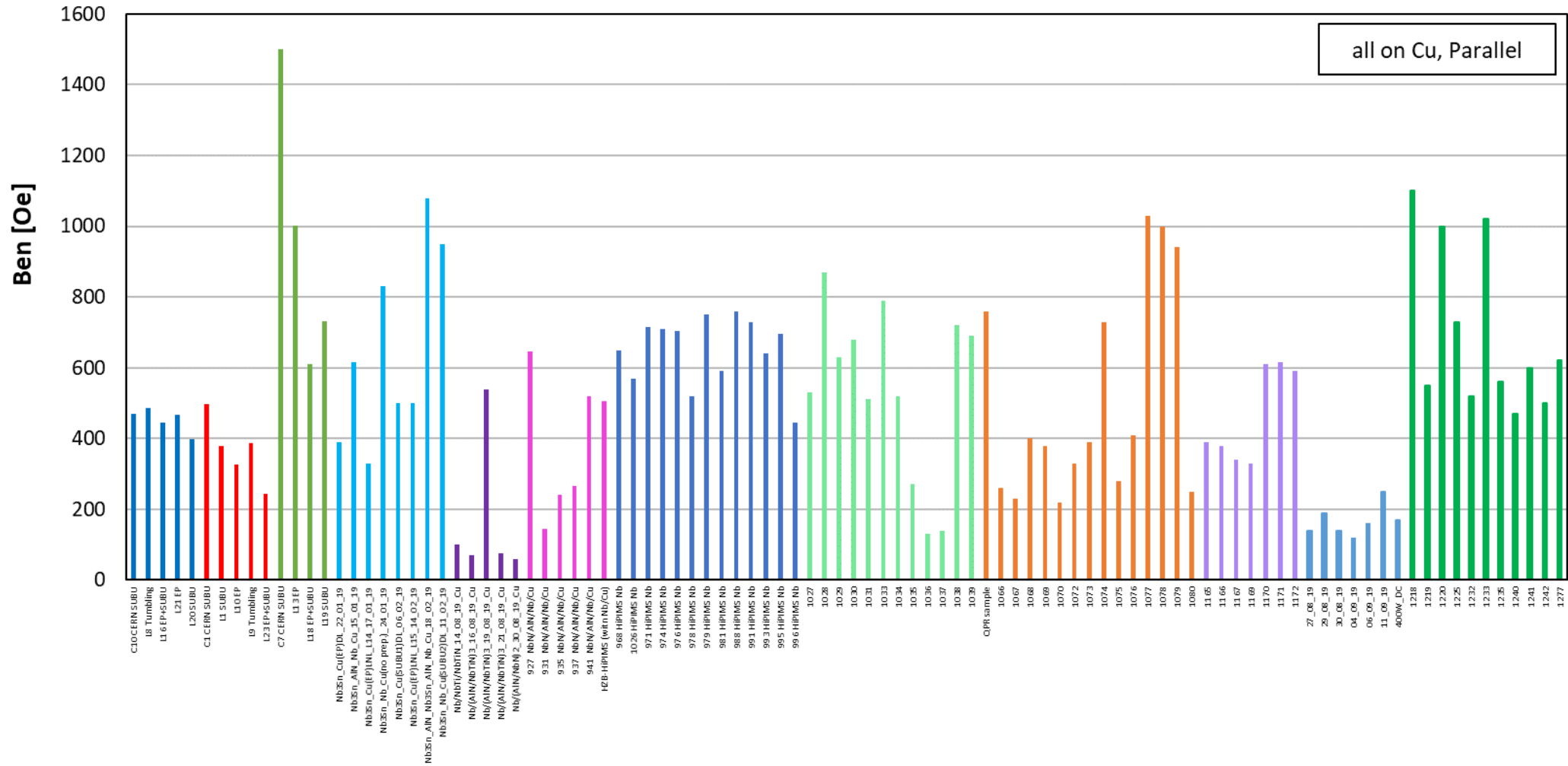
sample: **Ben [Oe] Tc [K]**
perp. Parallel VSM

HiPIMS Nb (on Cu)	27_08_19		140	9.5	
	29_08_19		190	9.55	
	STFC Daresbury		140	9.55	
	22.7.2020 series		120	9.6	
	Reza Valizadeh		160	9.55	
	11_09_19		220 - 370	9.5	
	400W_DC		170	9.55	
HiPIMS Nb (on Cu)	1218		1100	9.35	
	1219		550	9.4 Rer	
	1220		1000	9.45	
	1225		730	9.35	
	Uni Siegen		520	9.5	
	4.9.2020 series		1020	9.4	
	Stewart Leith		560	9.4	
	1240		470	9.5	
	1241		600	9.45	
	1242		500	9.6	
	1277		620	9.25 Rer	
	HiPIMS NbN (on Cu)	1284		80	14.6
		1285		130	16.5
		1287		275	15.5
		1288		250	15.5
		1291		80	10
		1295		90	~ 13
1296			280	14.6	
1325			140	14.6	
1327			220	13.5	
Uni Siegen					
6.10.2020 series					
Stewart Leith					

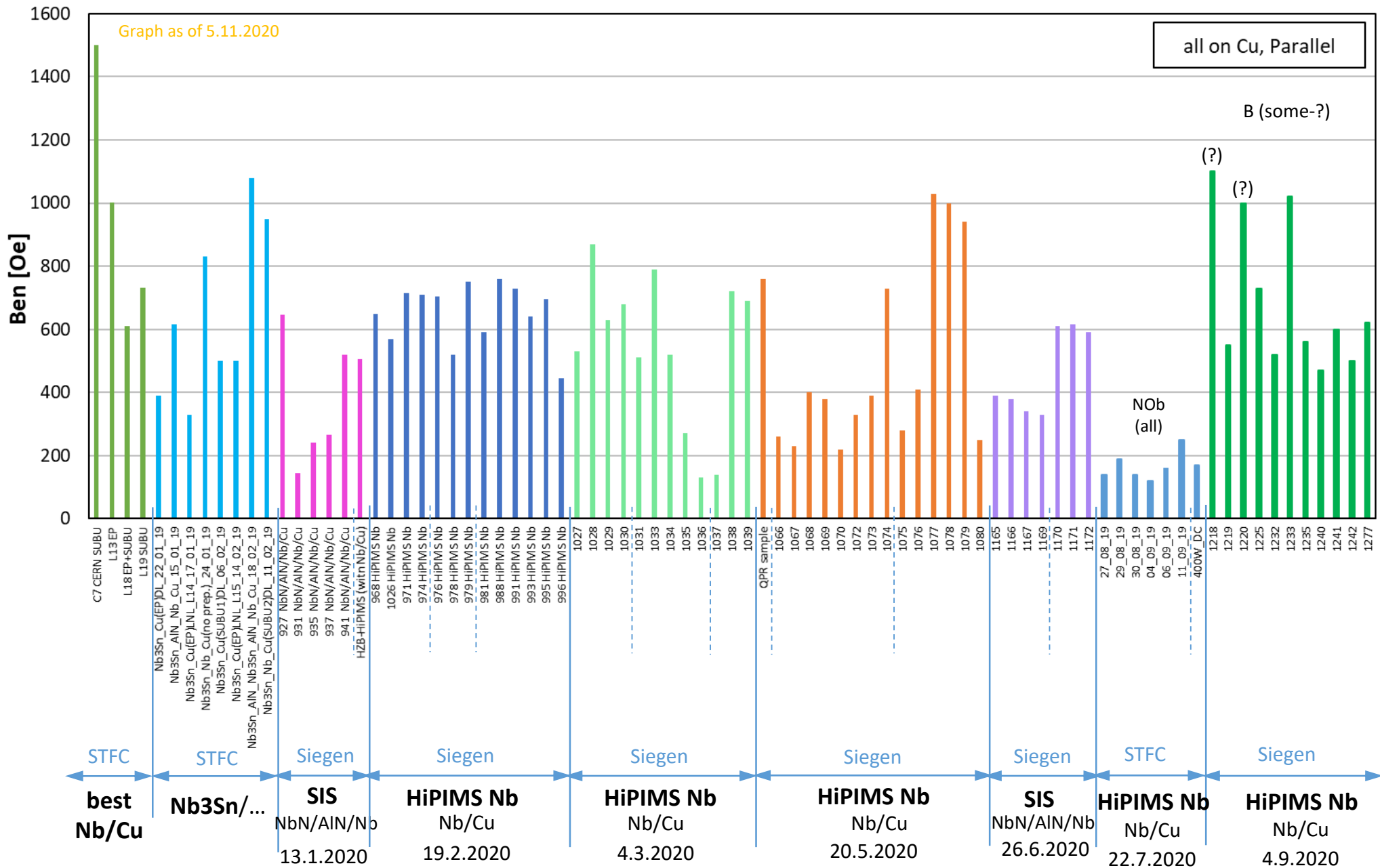
sample: **Ben [Oe] Tc [K]**
perp. Parallel VSM

HiPIMS Nb	NbTiN_19_02_20_Cu		
NbTiN	NbTiN_19_02_20_VG		
V3Si	NbTiN_19_02_20_Ta		
	Nb_14_07_20_Cu		
Substrates:	Nb_14_07_20_Ta		
Cu	Nb_16_07_20_Cu		
Sapphire	Nb_16_07_20_Ta		
Tantal	Nb_22_07_20_Cu		
VG - Vitreous graphite	Nb_22_07_20_Ta		
	V3Si_24_07_20_Cu		
	V3Si_24_07_20_Ta		
	V3Si_24_07_20_Cu		
STFC Daresbury	V3Si_28_07_20_Cu		
18.9.2020 series	V3Si_28_07_20_VG		
Reza Valizadeh	V3Si_28_07_20_Ta		
	Nb_31_07_20_Cu		
	Nb_31_07_20_Sapp		
	Nb_31_07_20_Ta		
	Nb_01_08_20_Cu		
	Nb_01_08_20_Sapp		
	Nb_01_08_20_Ta		
	Nb_06_08_20_Cu		
	Nb_06_08_20_Sapp		
	Nb_06_08_20_Ta		
HiPIMS NbN	1467		
HiPIMS ML: Nb/NbN	1468		
Substrate:	1472		
Cu	1475		
	1477		
Uni Siegen	1496_ML		
3.11.2020 series	1497_ML		
Stewart Leith	1498_ML		

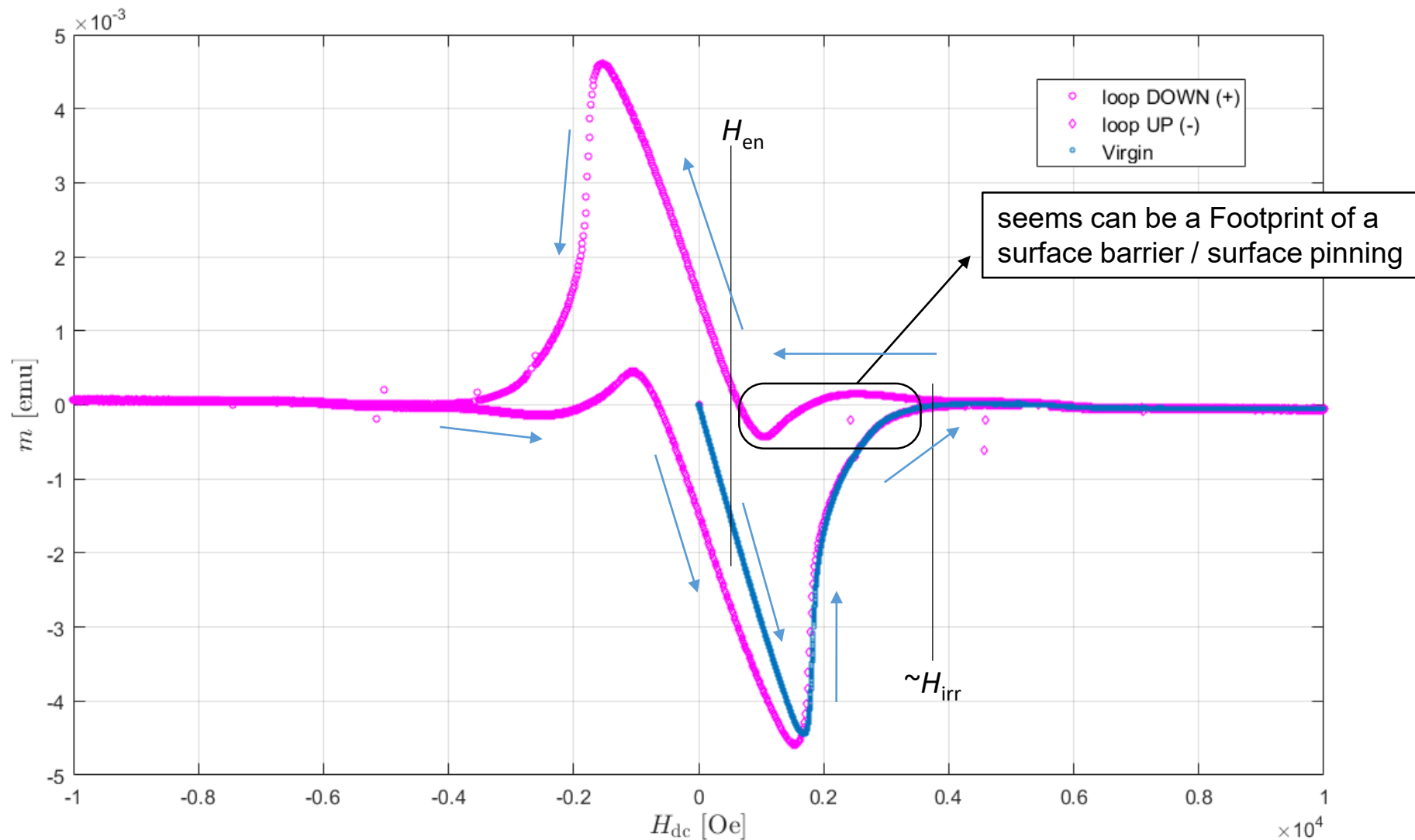
Selected films on Cu substrates:



Narrow-Selected films on Cu substrates:



Shape of magnetization loop

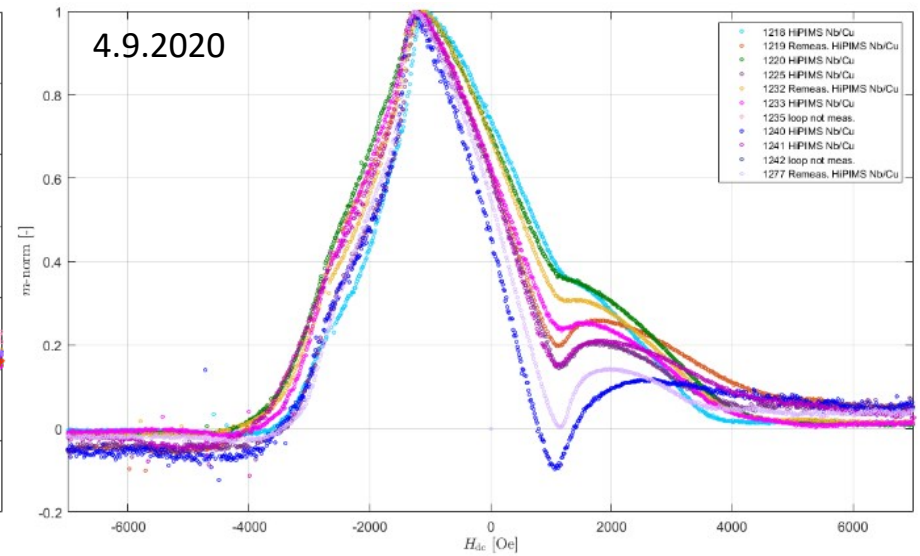
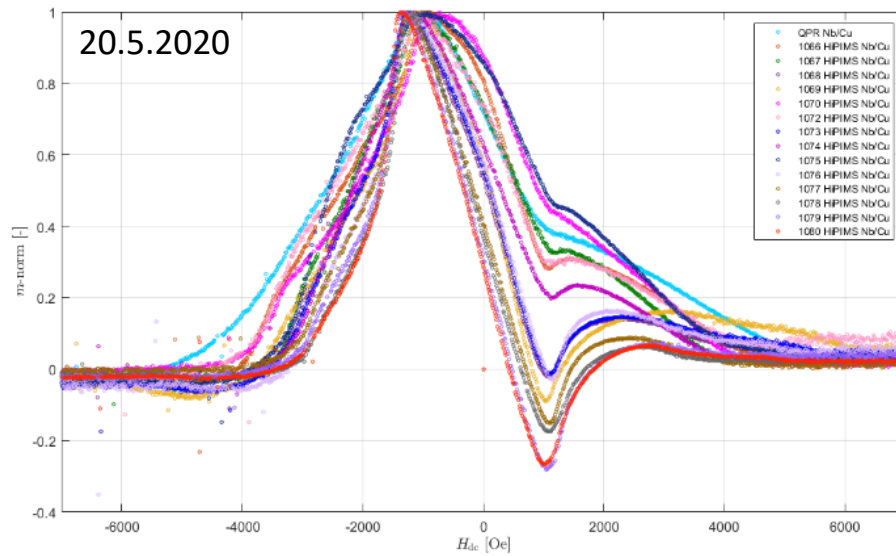
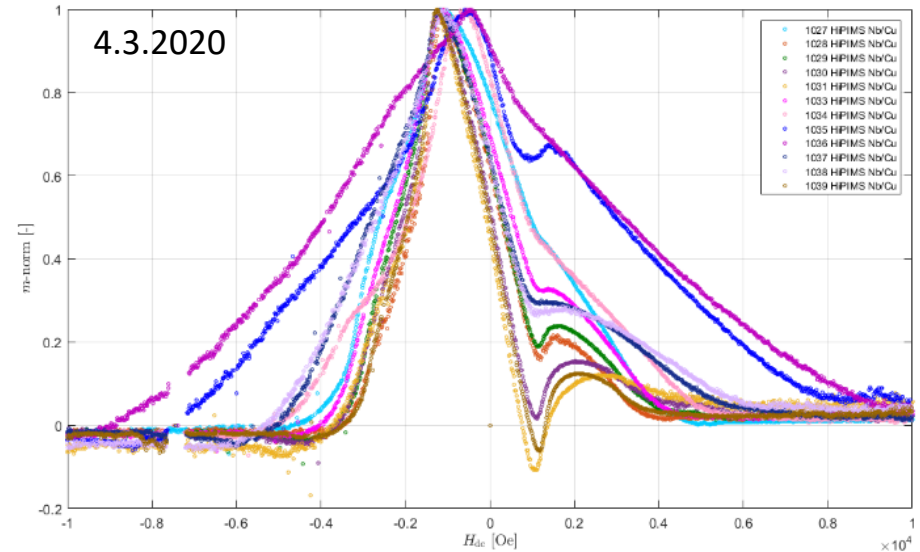
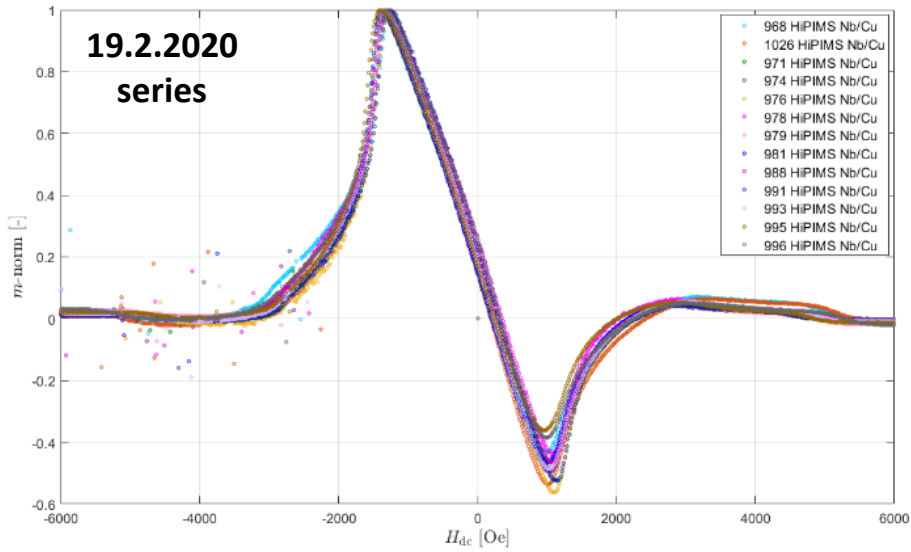


see e.g.: S B Roy et al, Supercond. Sci. Technol. 21 (2008) 065002

E H Brandt, Physica C 332 (2000) 99–107

A S Dhavale et al, Supercond. Sci. Technol. 25 (2012) 065014

HiPIMS Nb/Cu of Siegen Uni



Is there any significant difference in 'Surface quality' of 19.2.2020 vs. 4.3.2020,20.5.2020,4.9.2020 ?

FURTHER

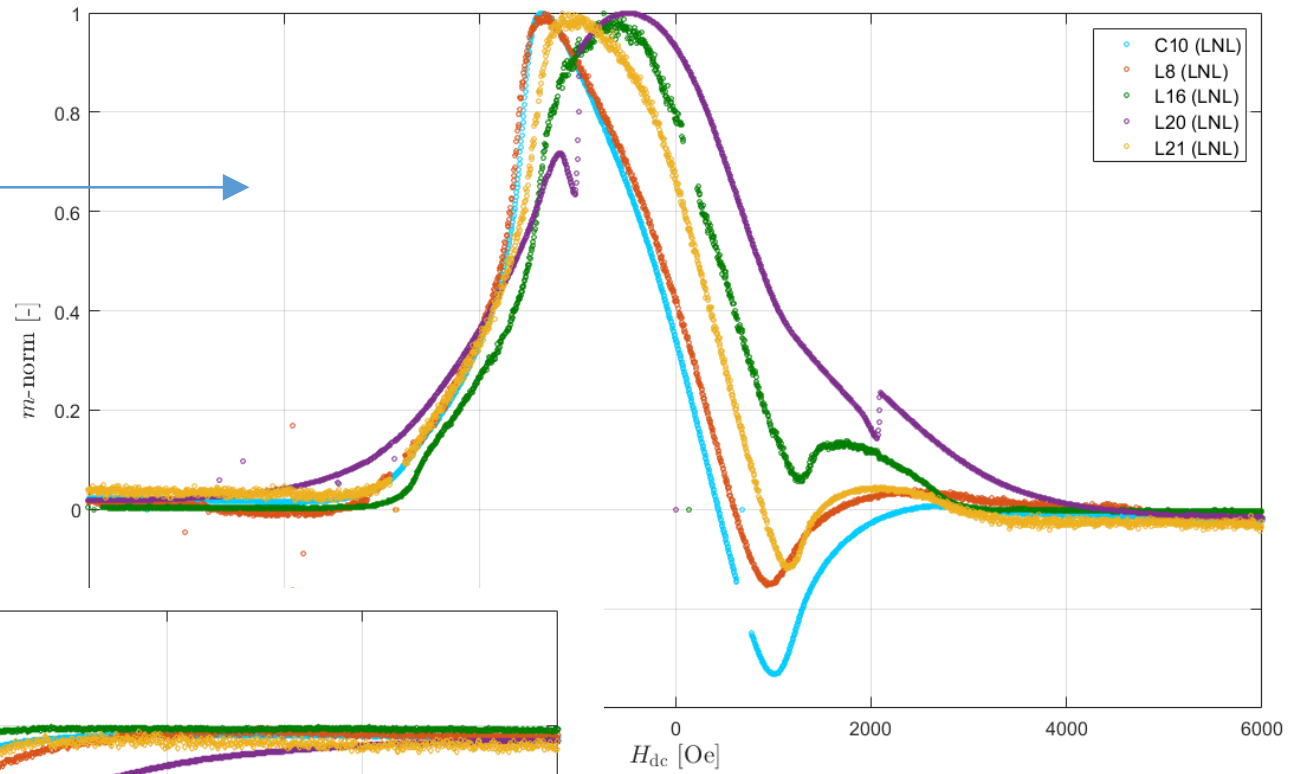
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Comparisons of mag. loops

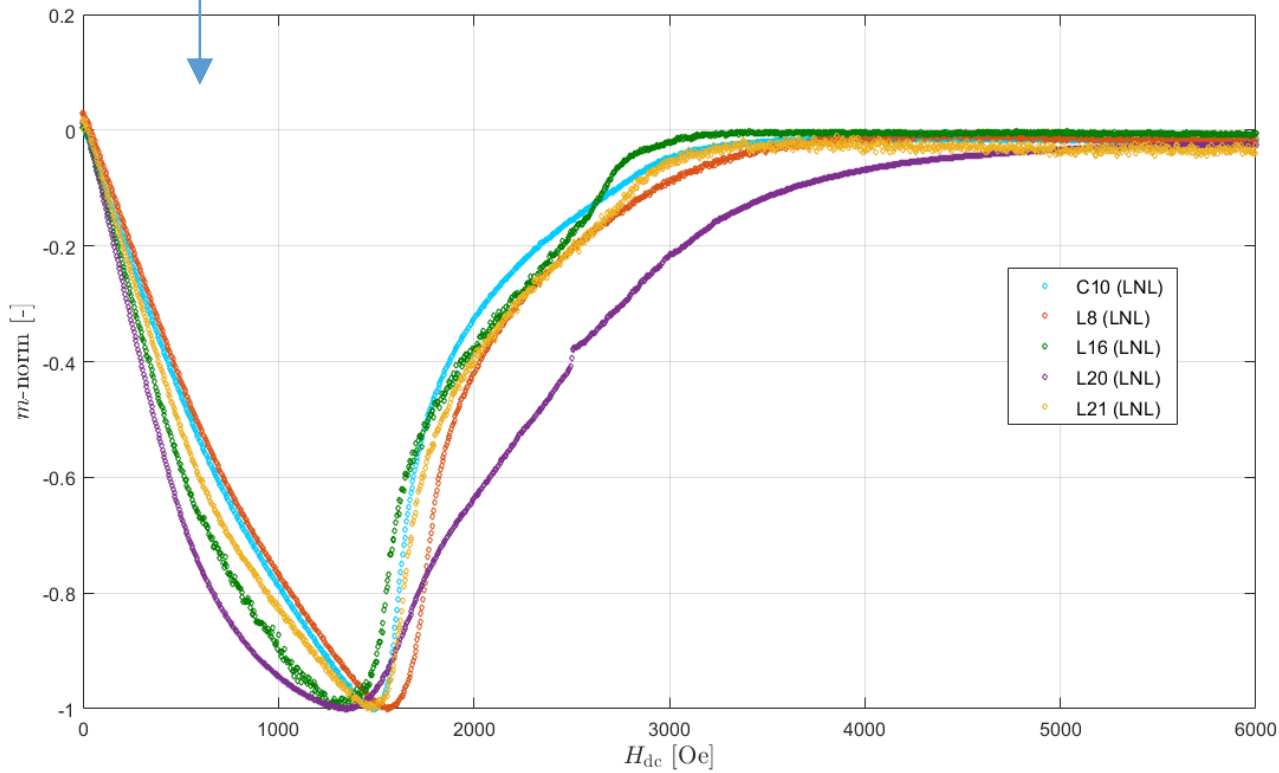
All series on Cu substrates

Nb/Cu INFN

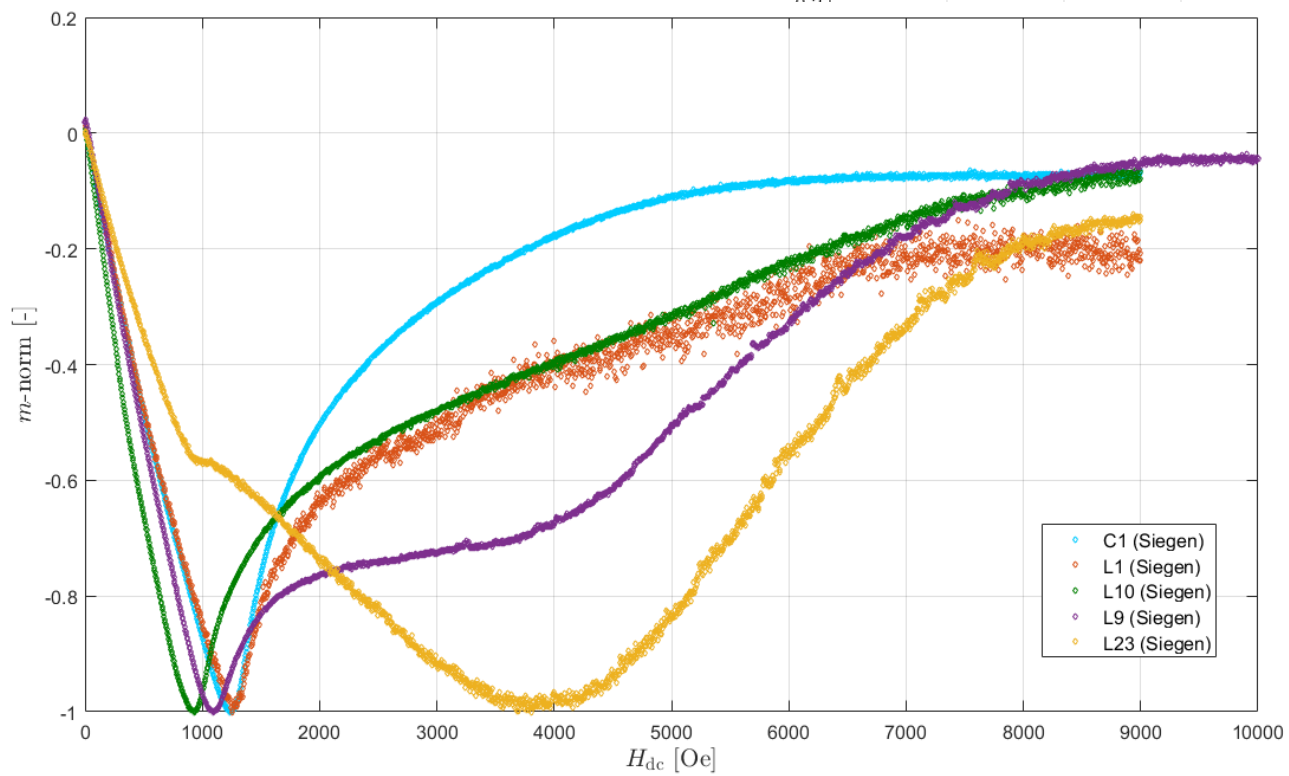
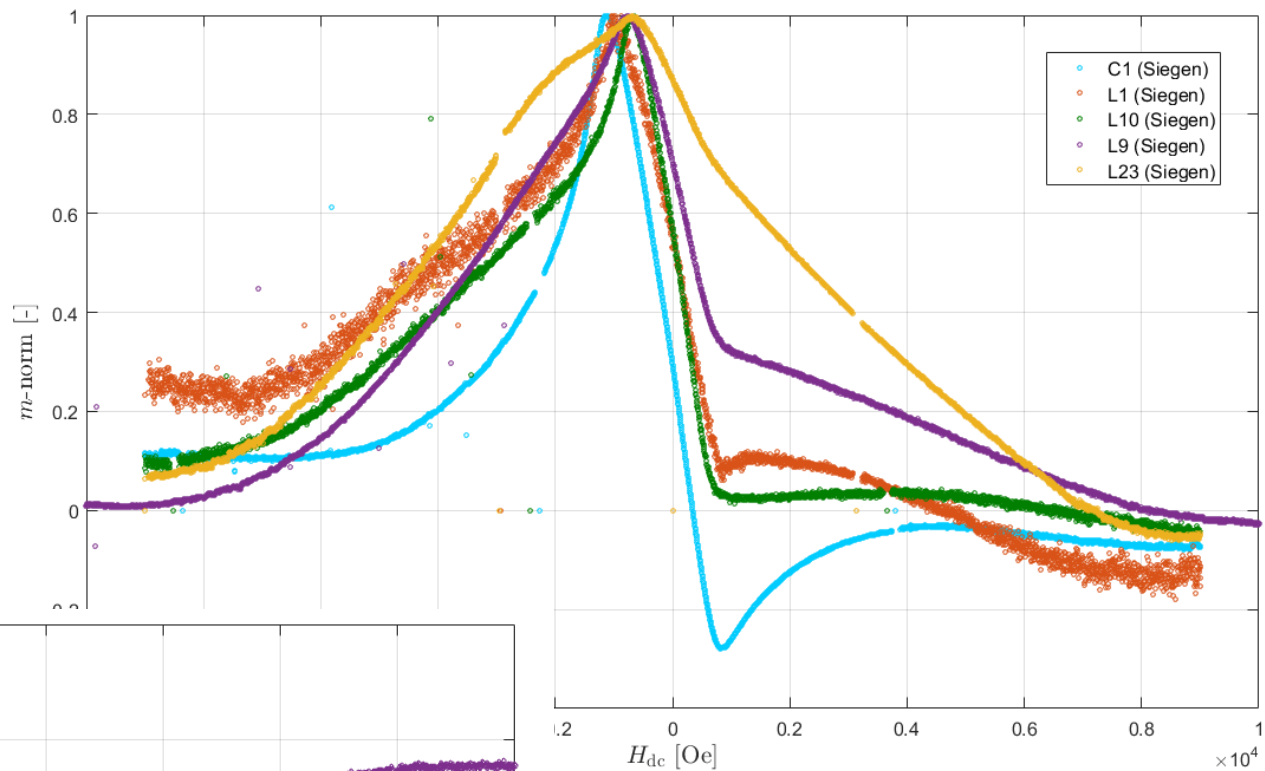
Loop – upper branch,
normalized to Max



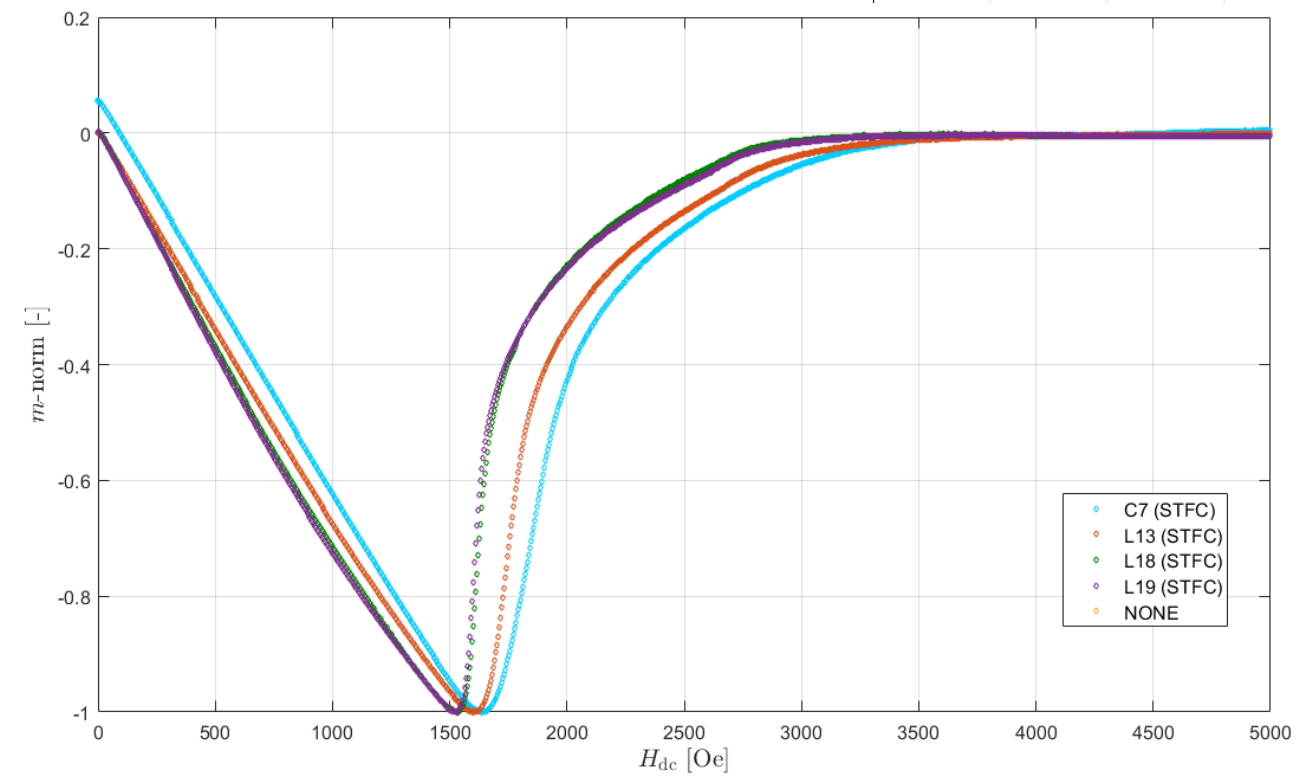
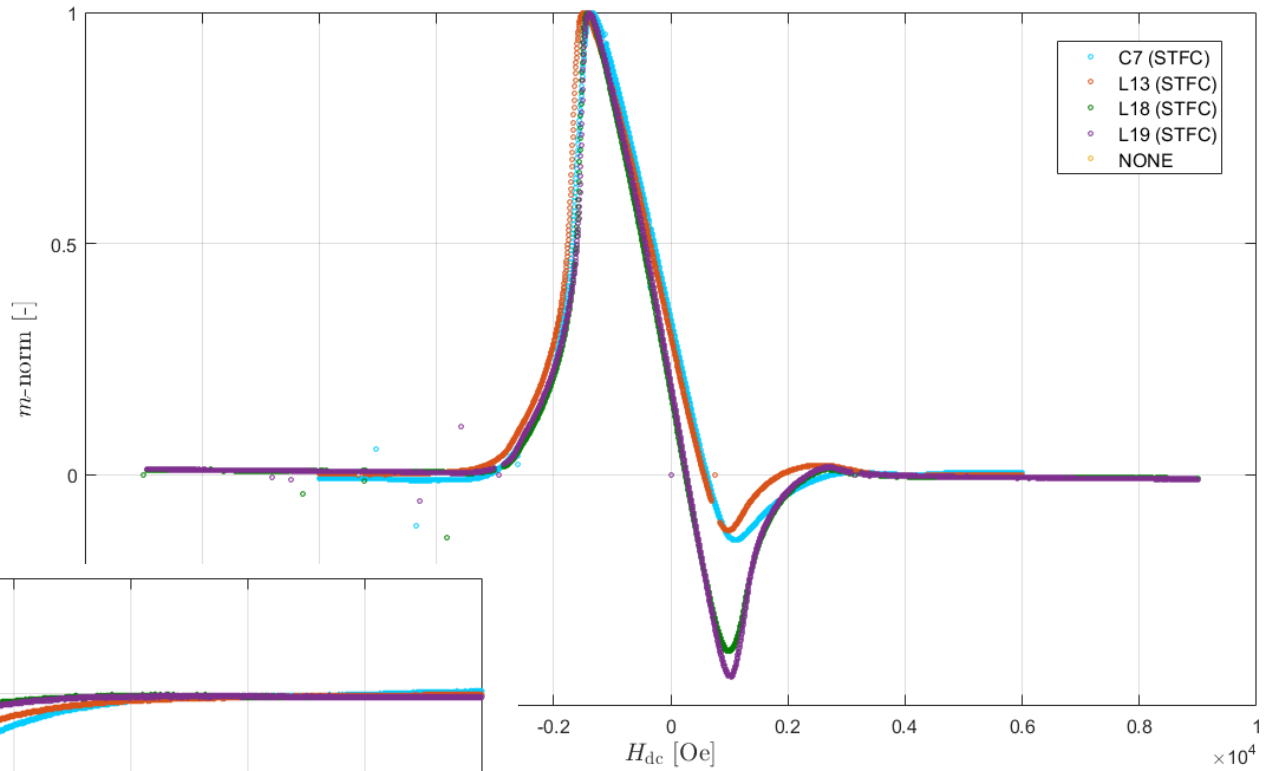
Virgin curve,
normalized to |Max|



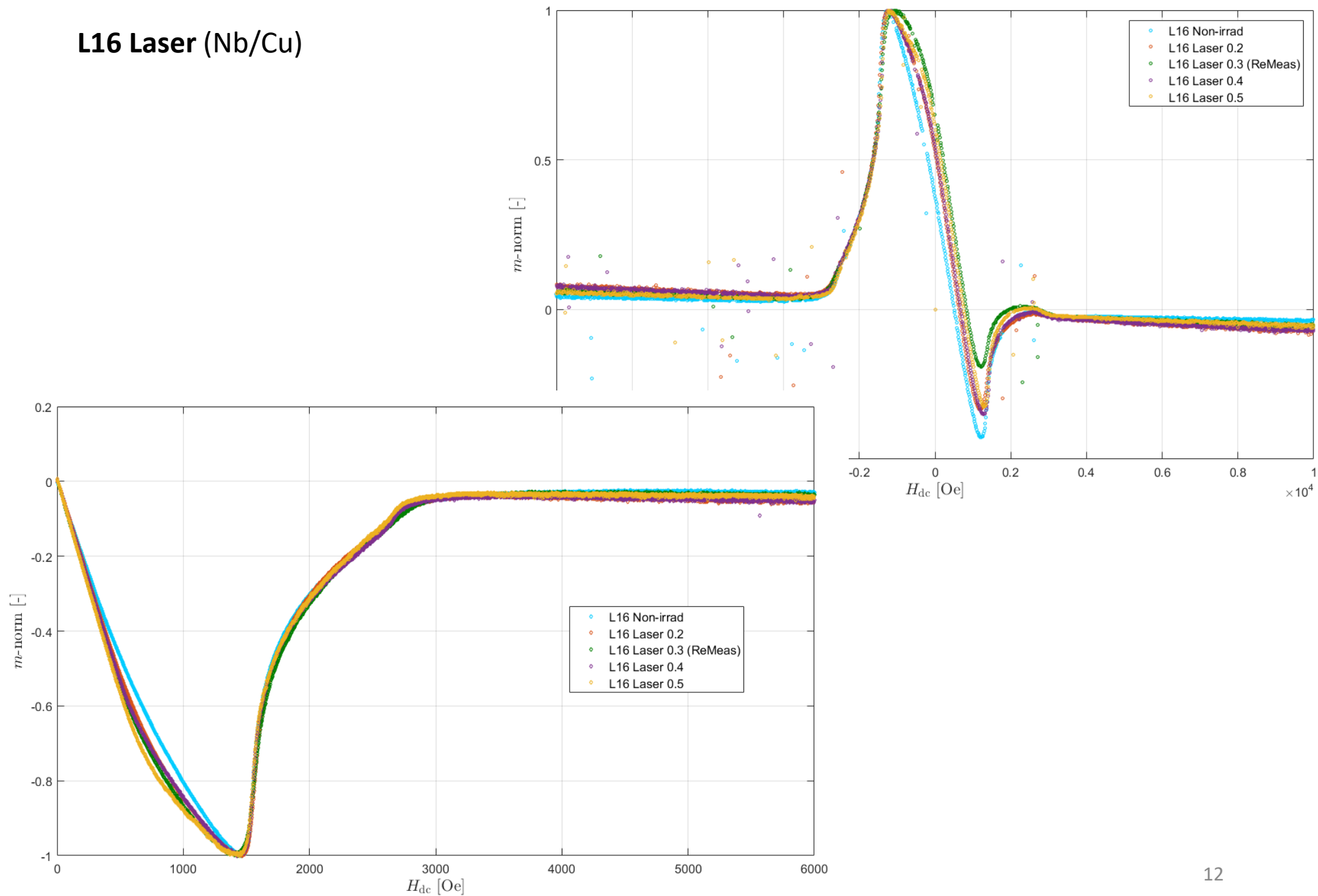
Nb/Cu Siegen Uni



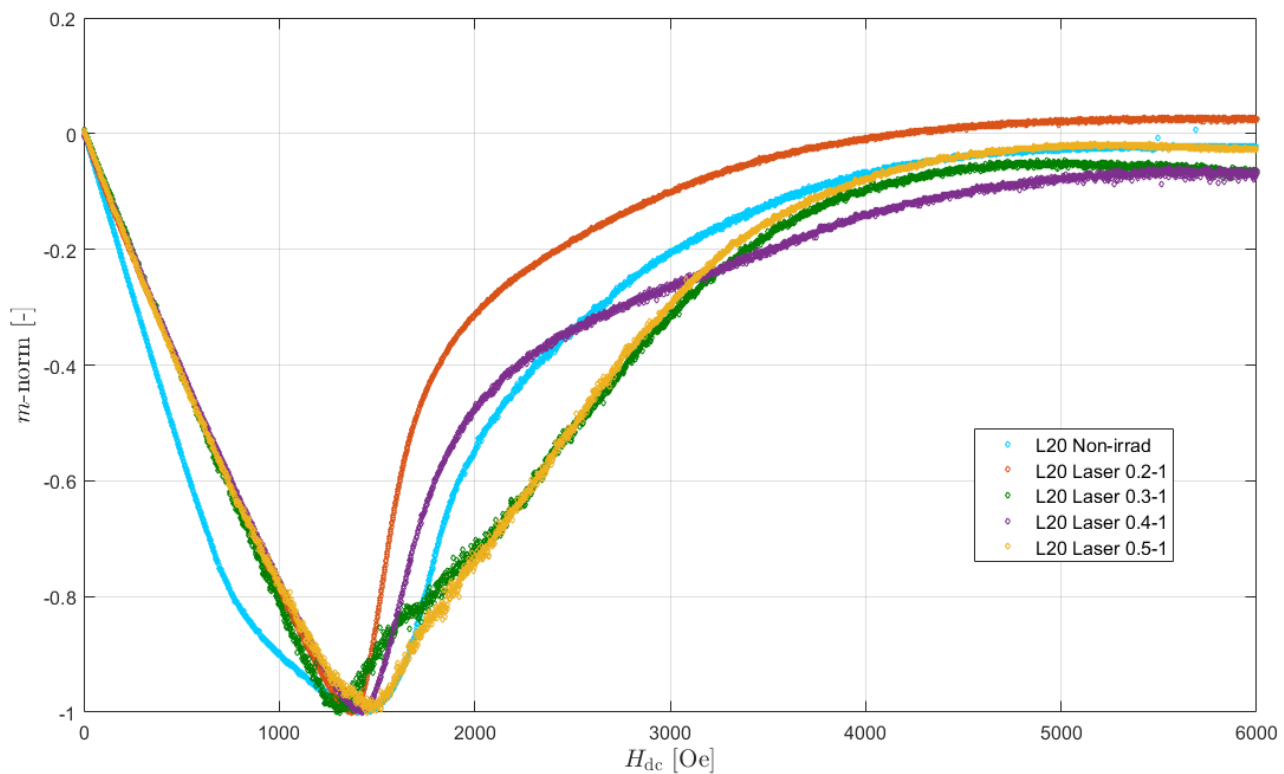
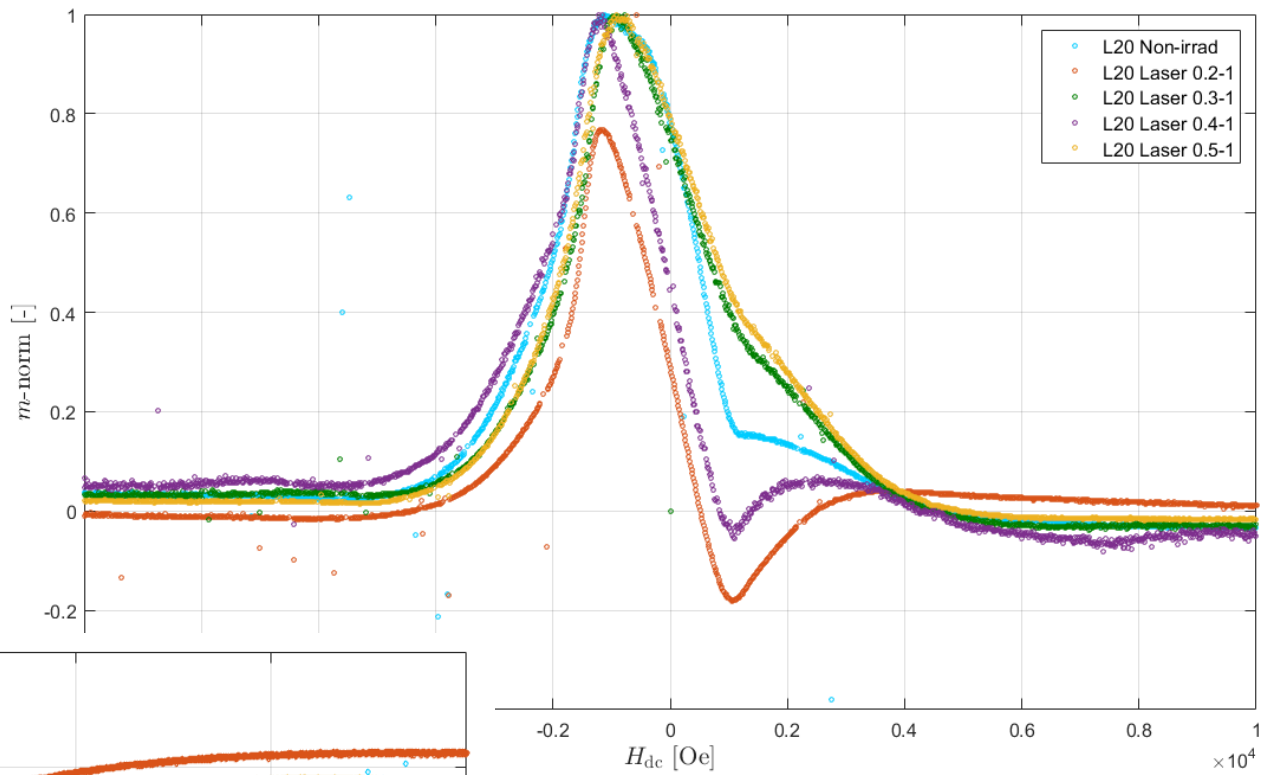
Nb/Cu STFC



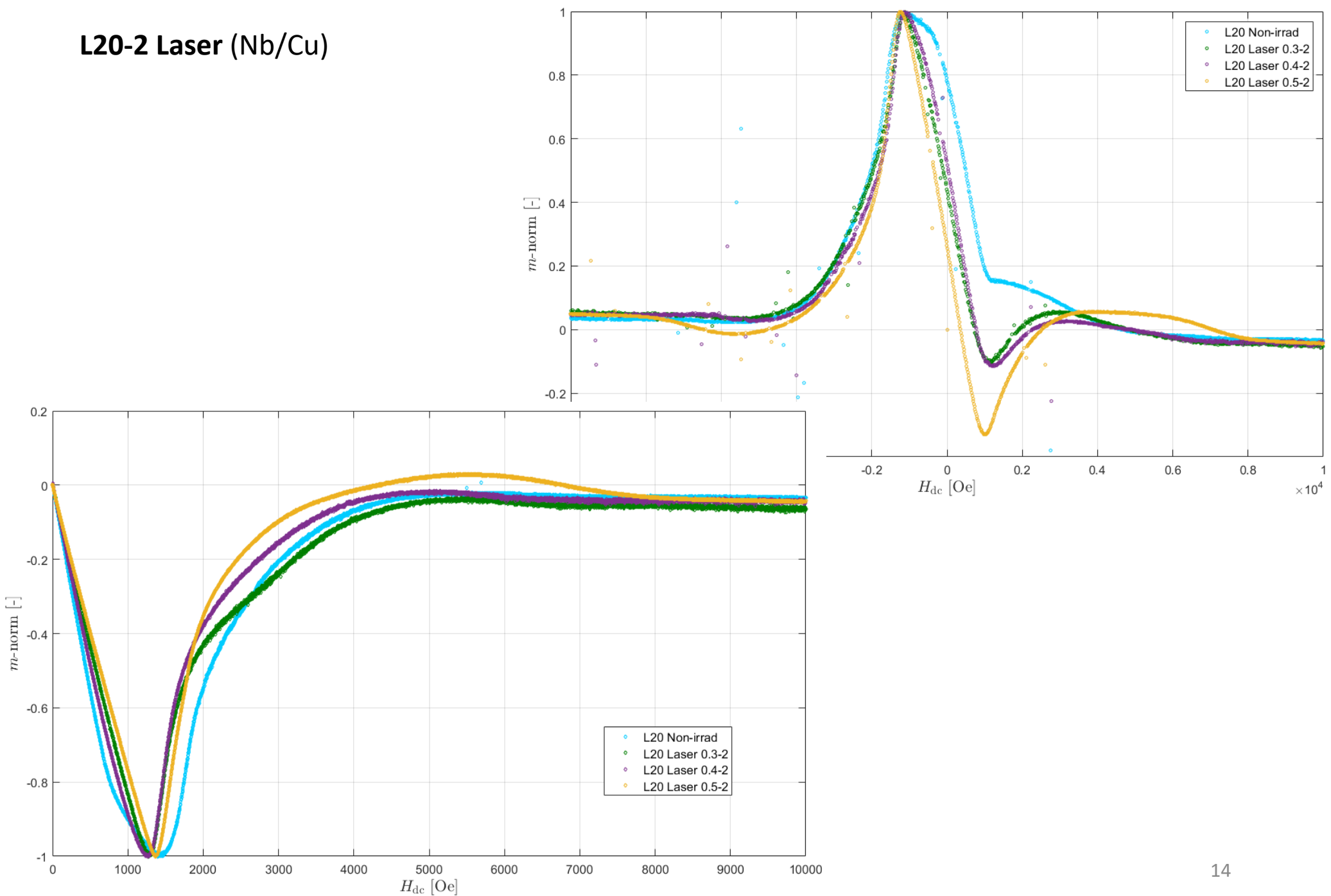
L16 Laser (Nb/Cu)



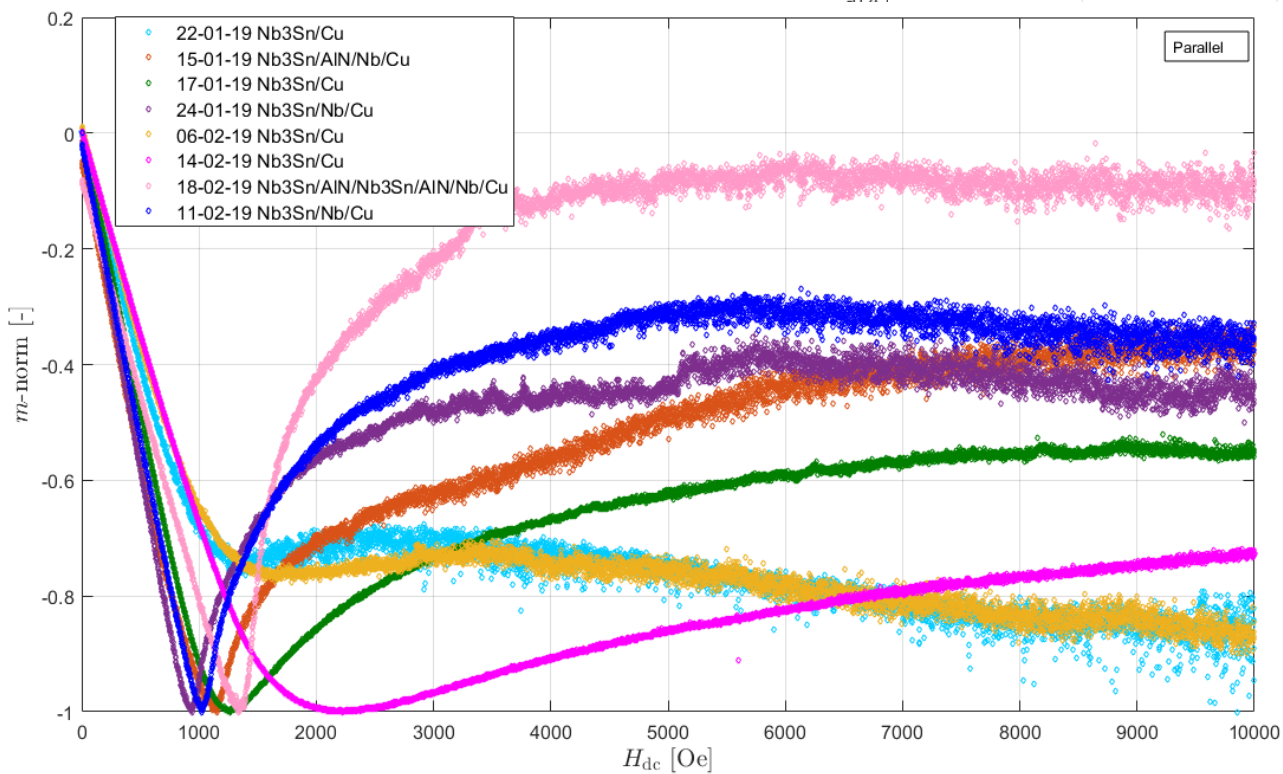
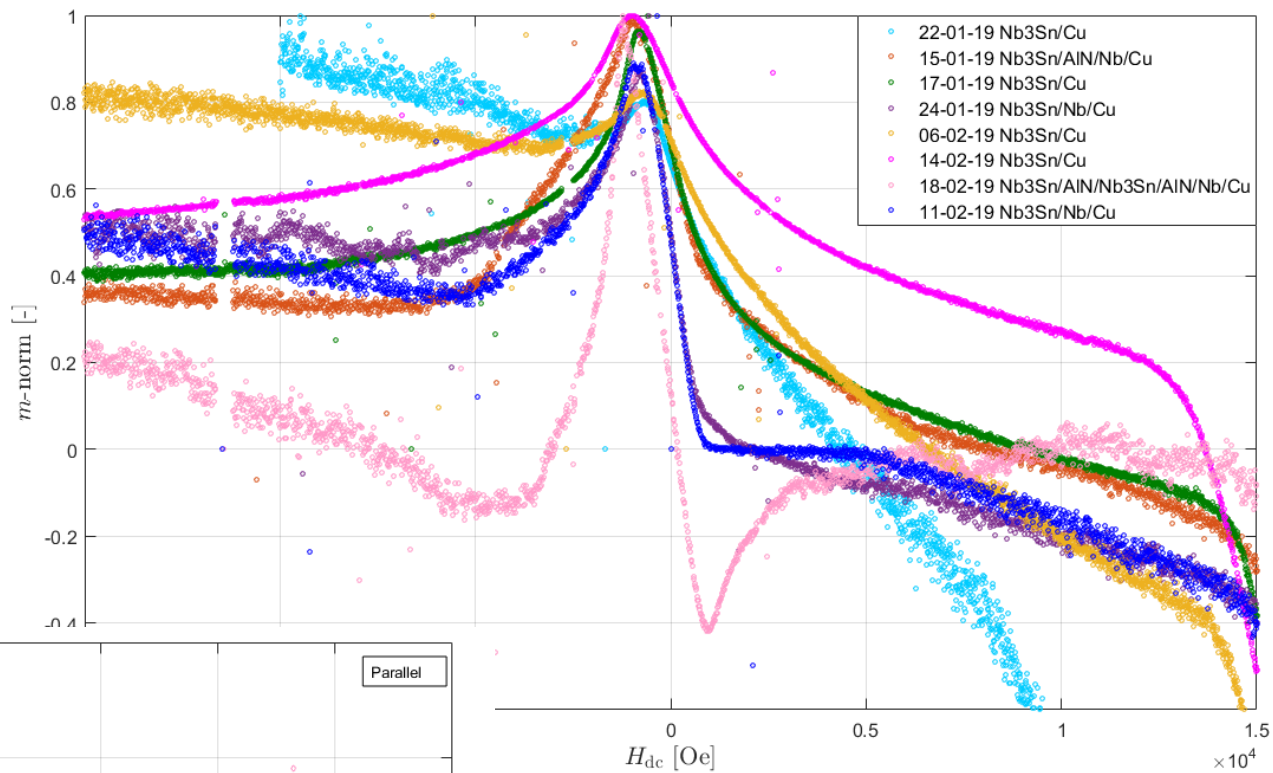
L20-1 Laser (Nb/Cu)



L20-2 Laser (Nb/Cu)

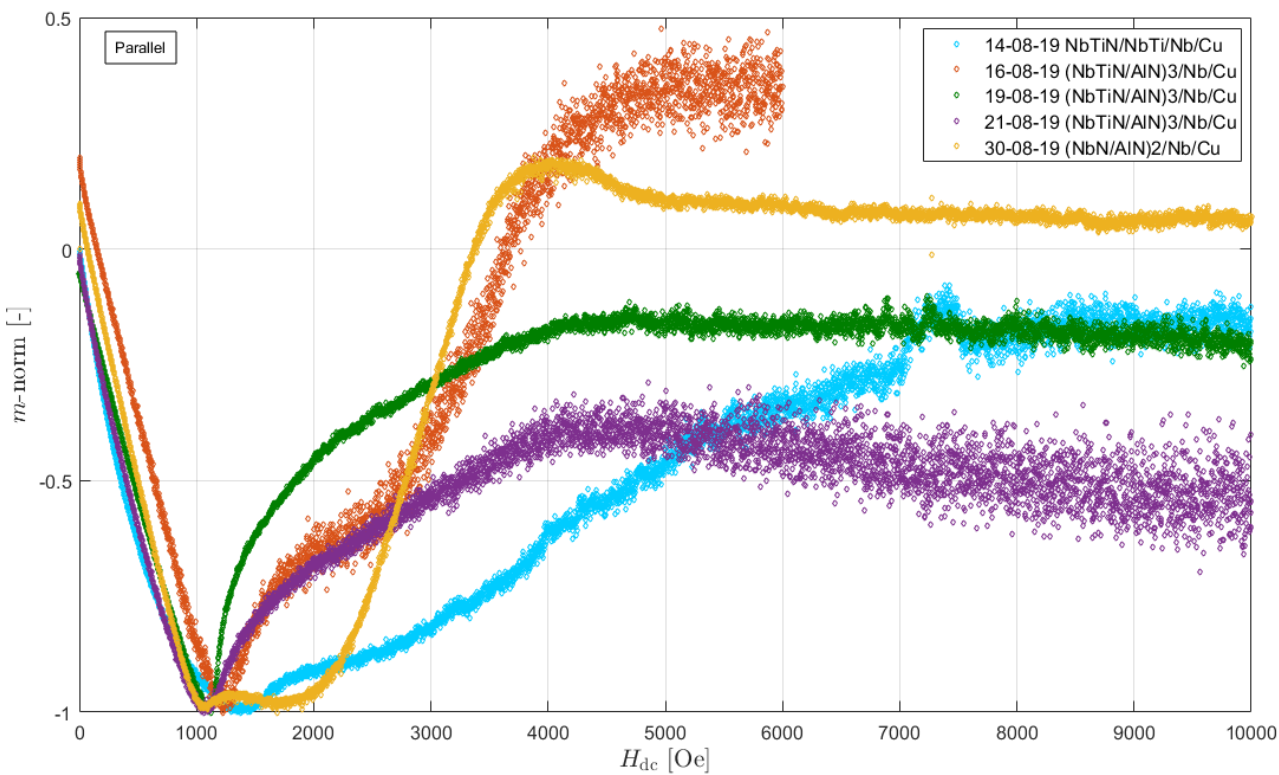
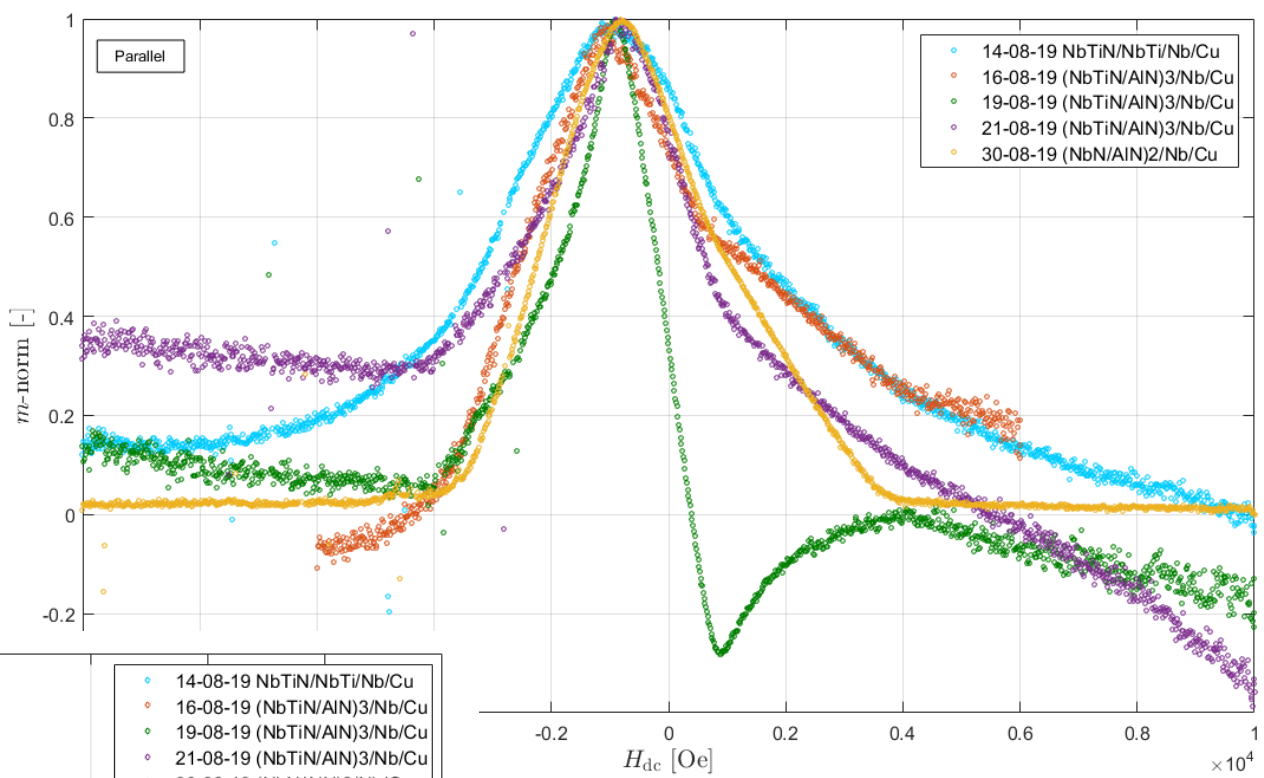


Nb₃Sn/.../Cu STFC



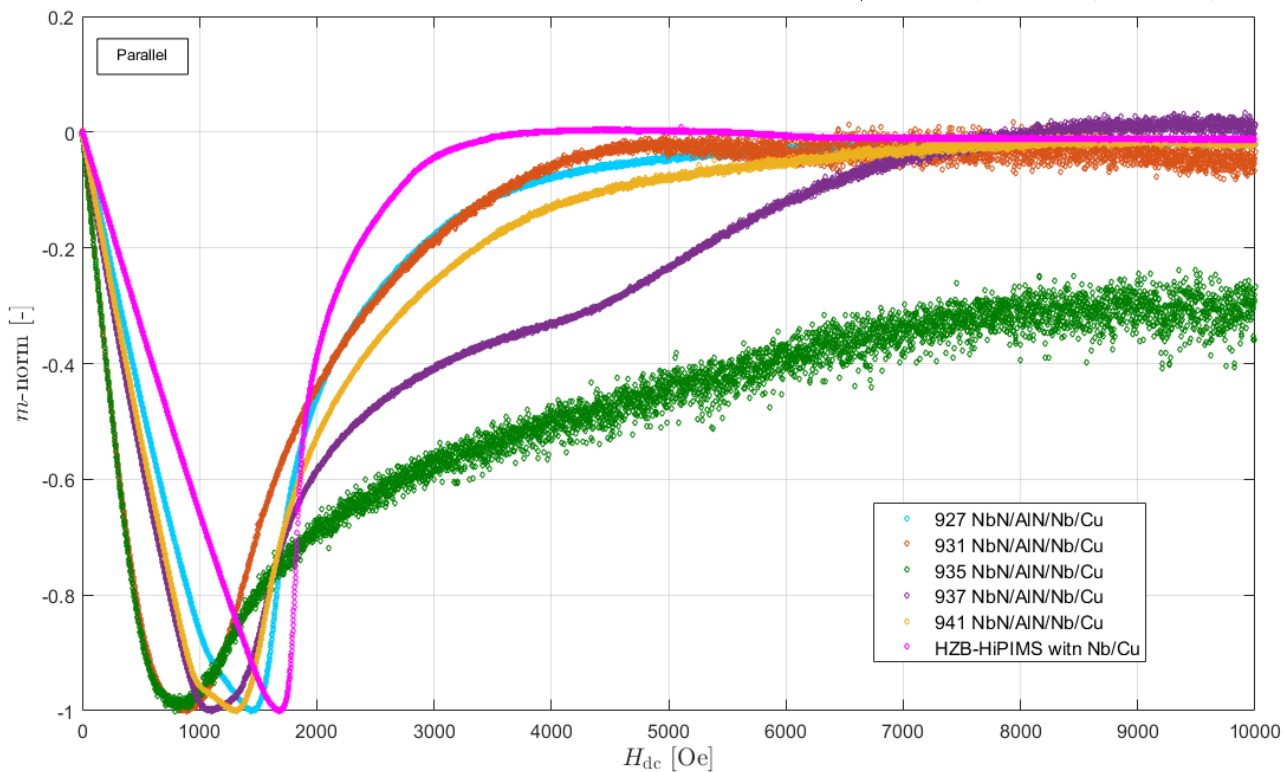
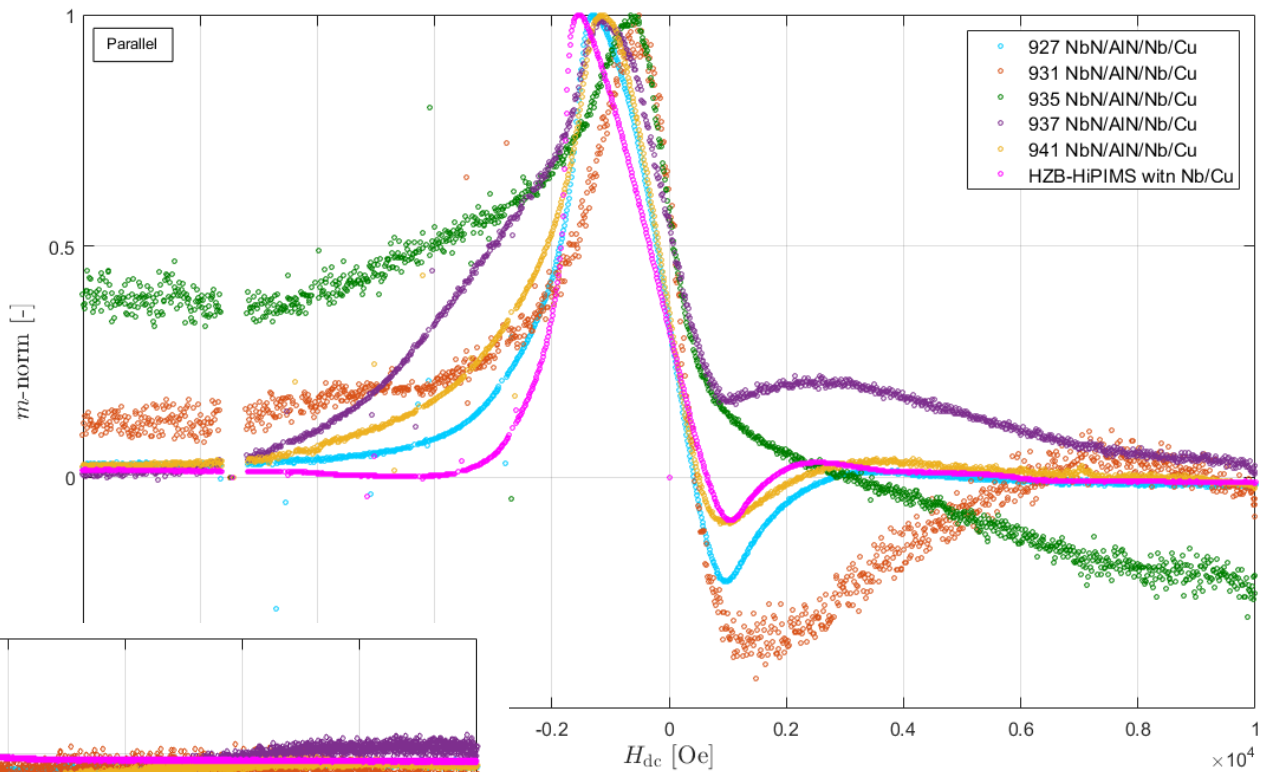
Multilayers STFC

NbTiN (NbN) / AlN / Nb / Cu



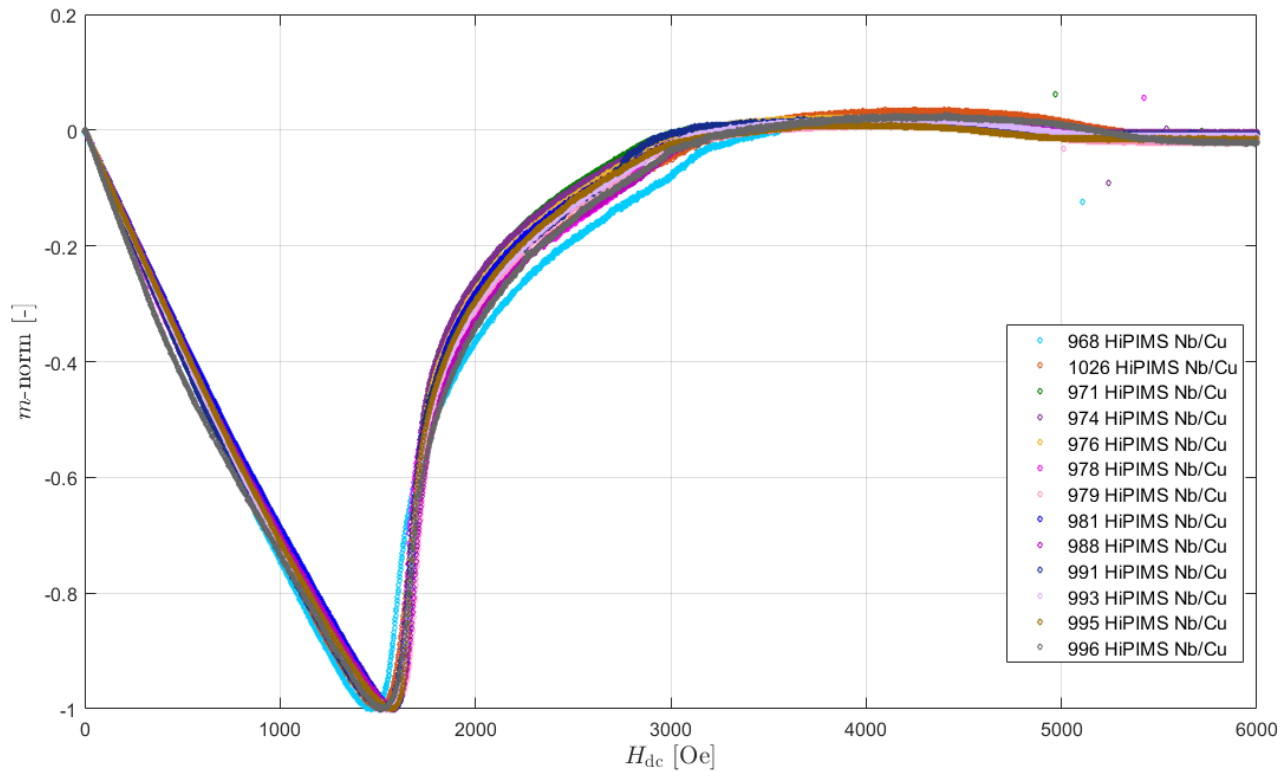
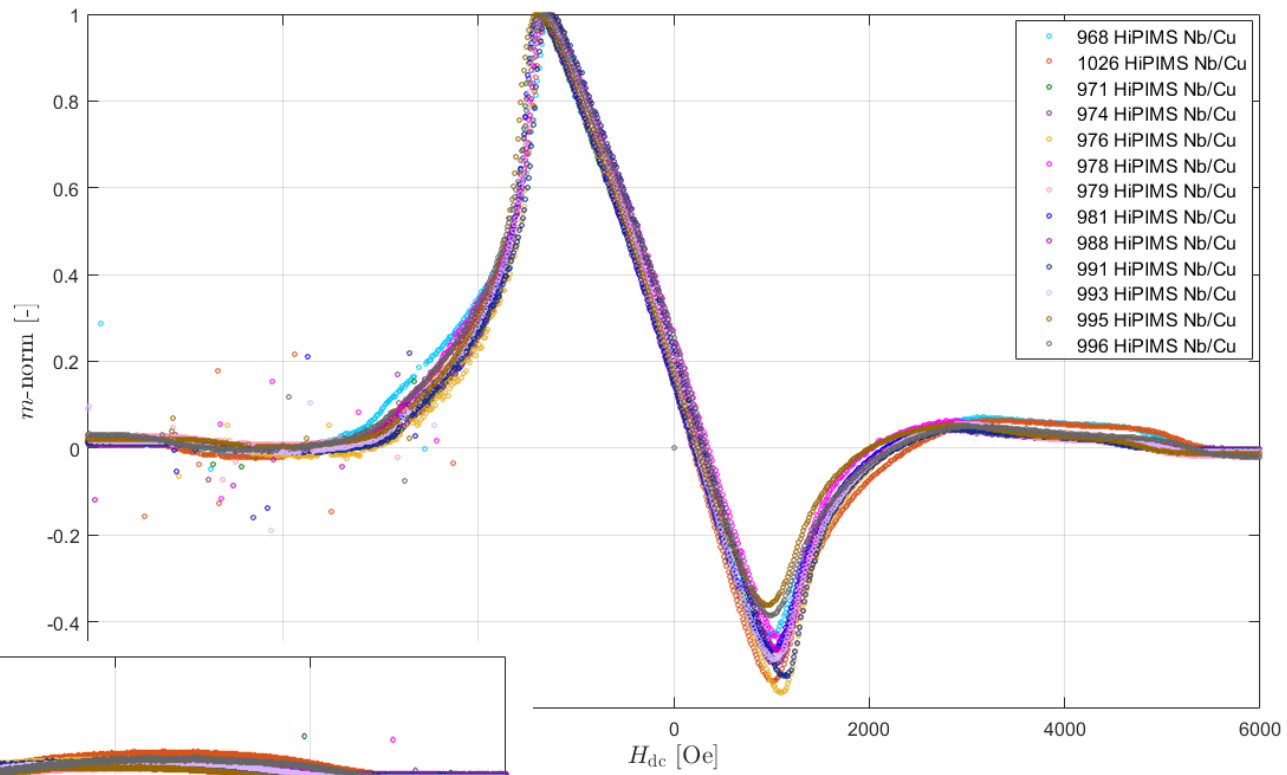
SIS Siegen Uni

NbN / AlN / Nb / Cu



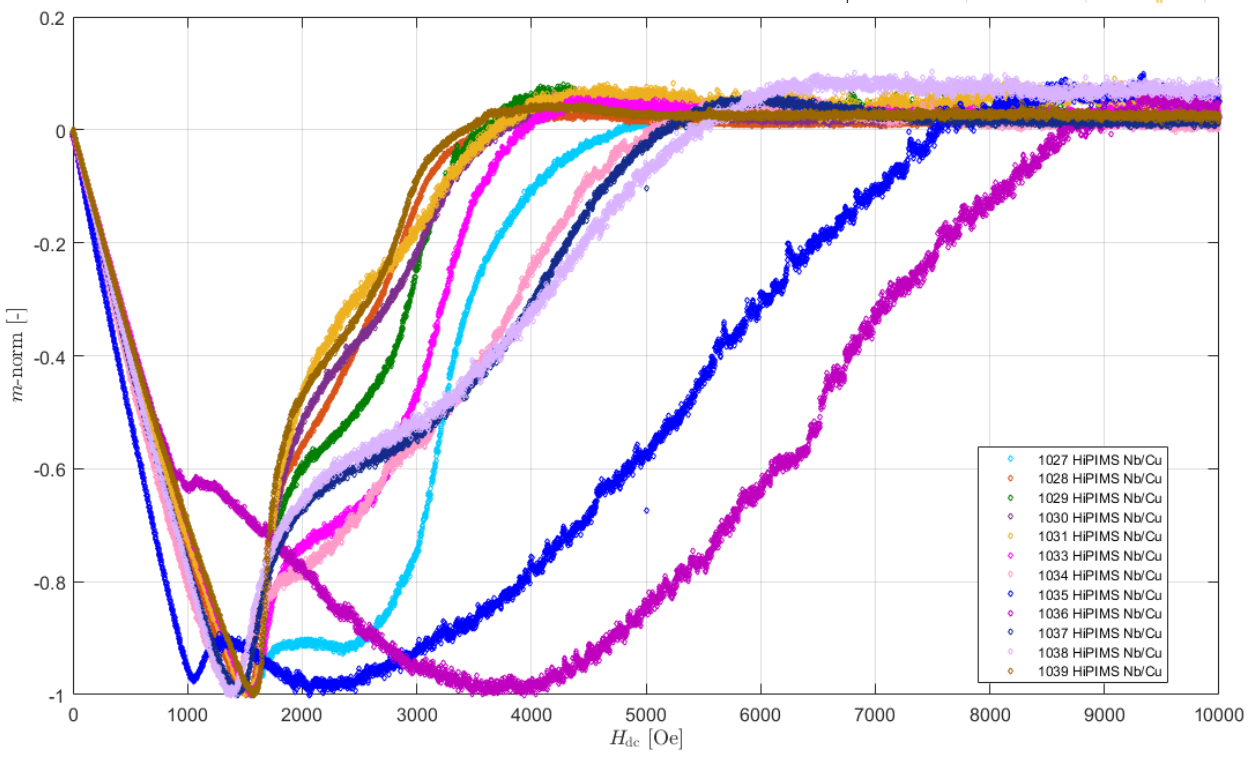
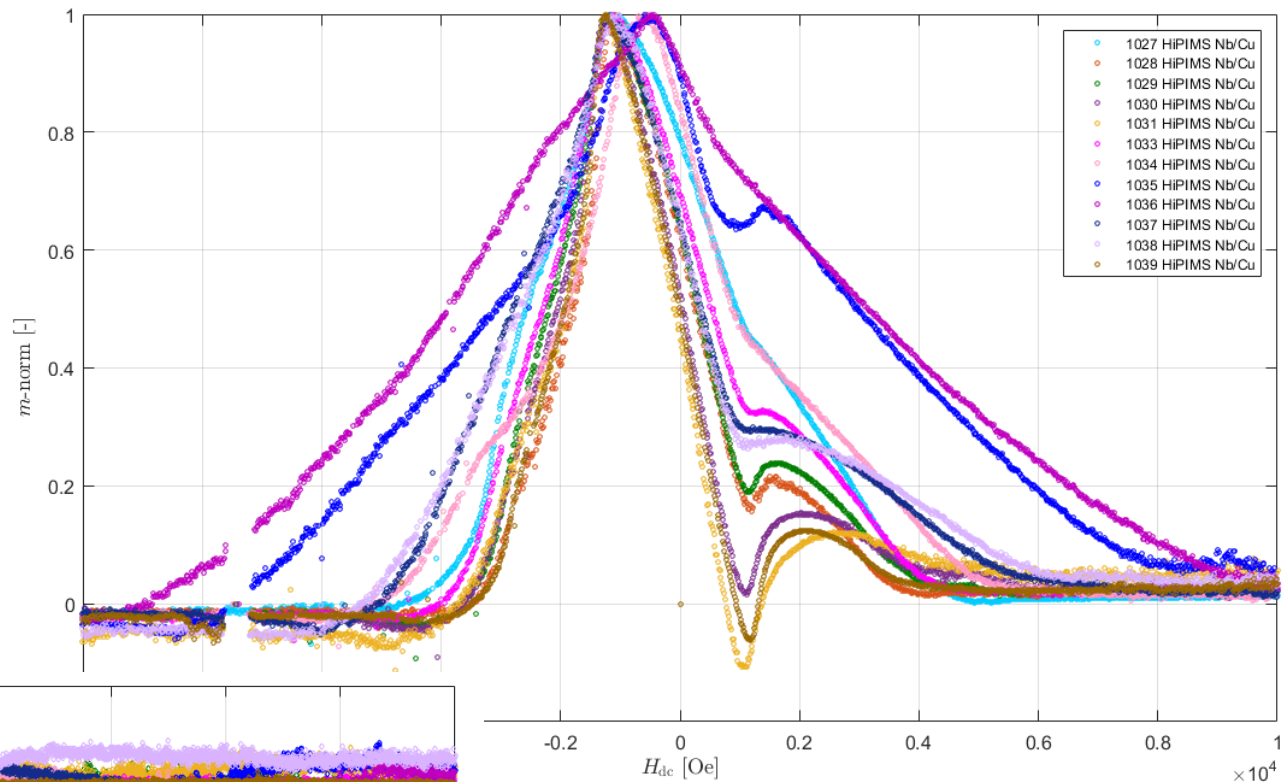
HiPIMS Nb 19.2.2020 series Siegen Uni

Nb / Cu



HiPIMS Nb 4.3.2020 series Siegen Uni

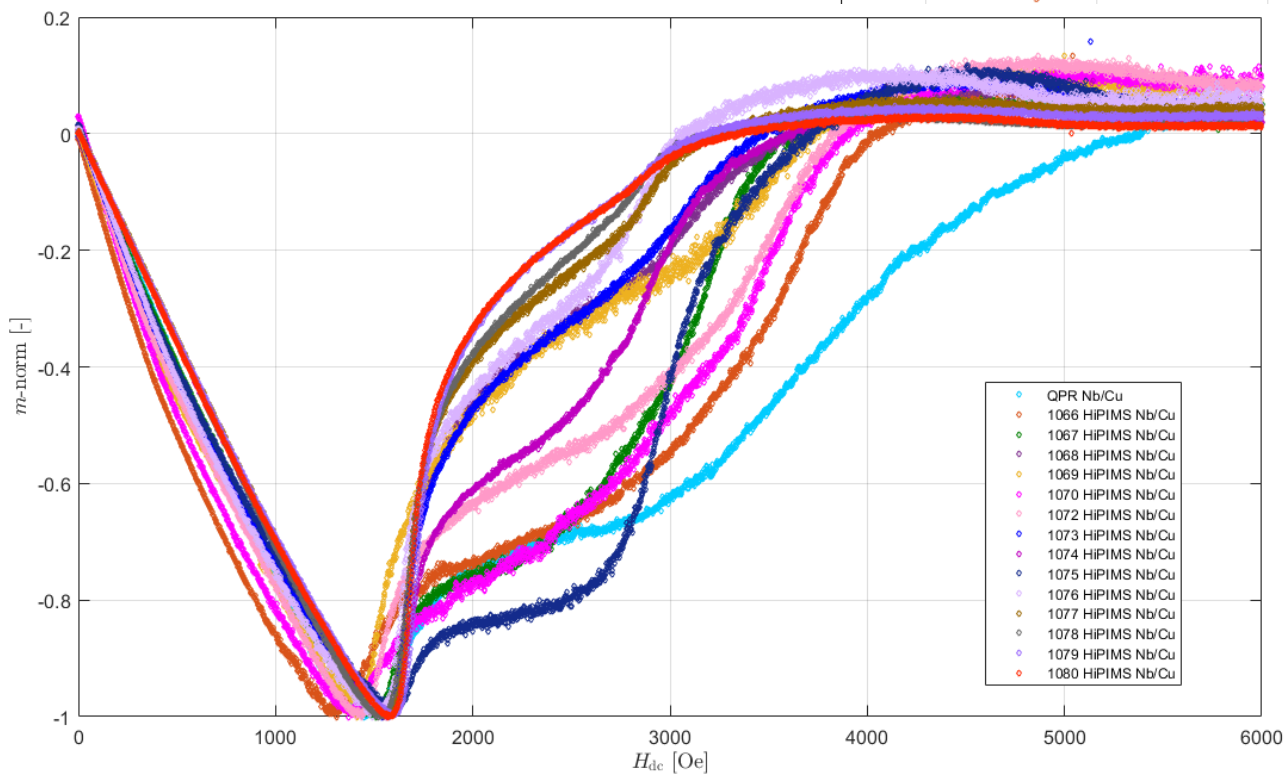
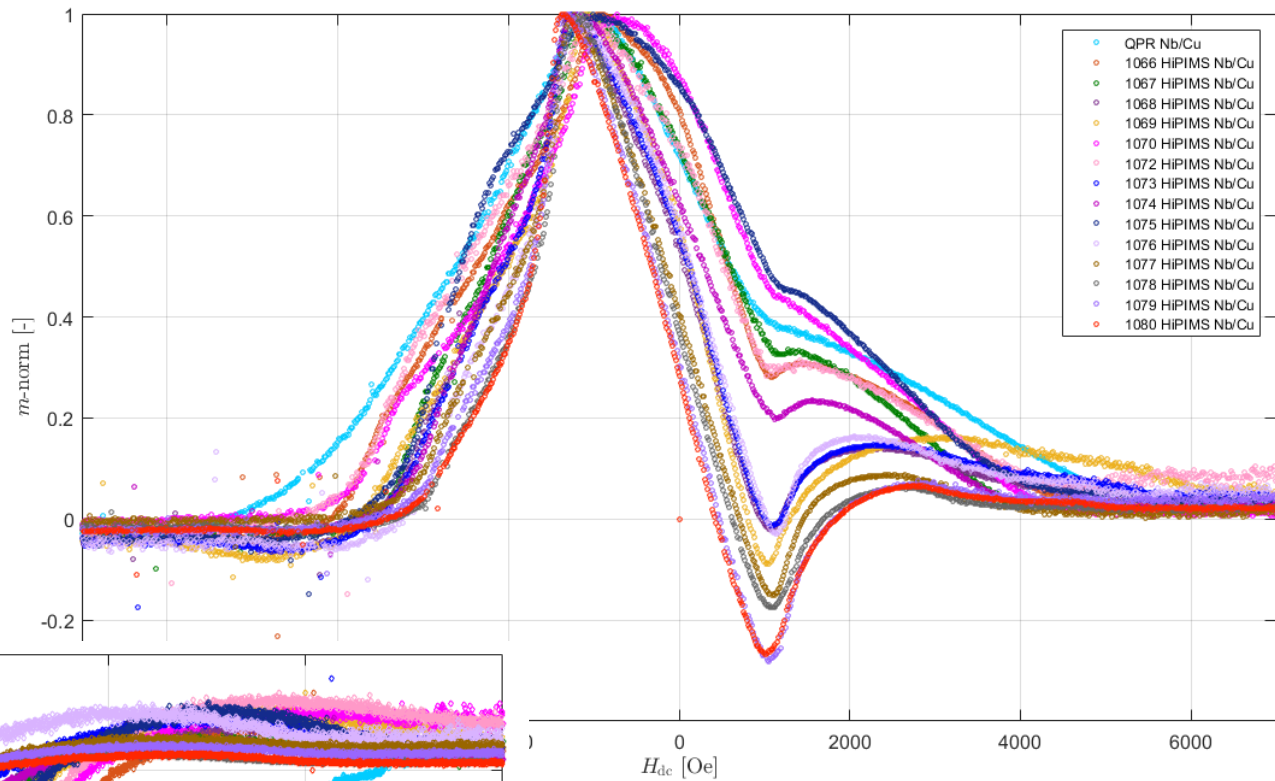
Nb / Cu



HiPIMS Nb 20.5.2020 series

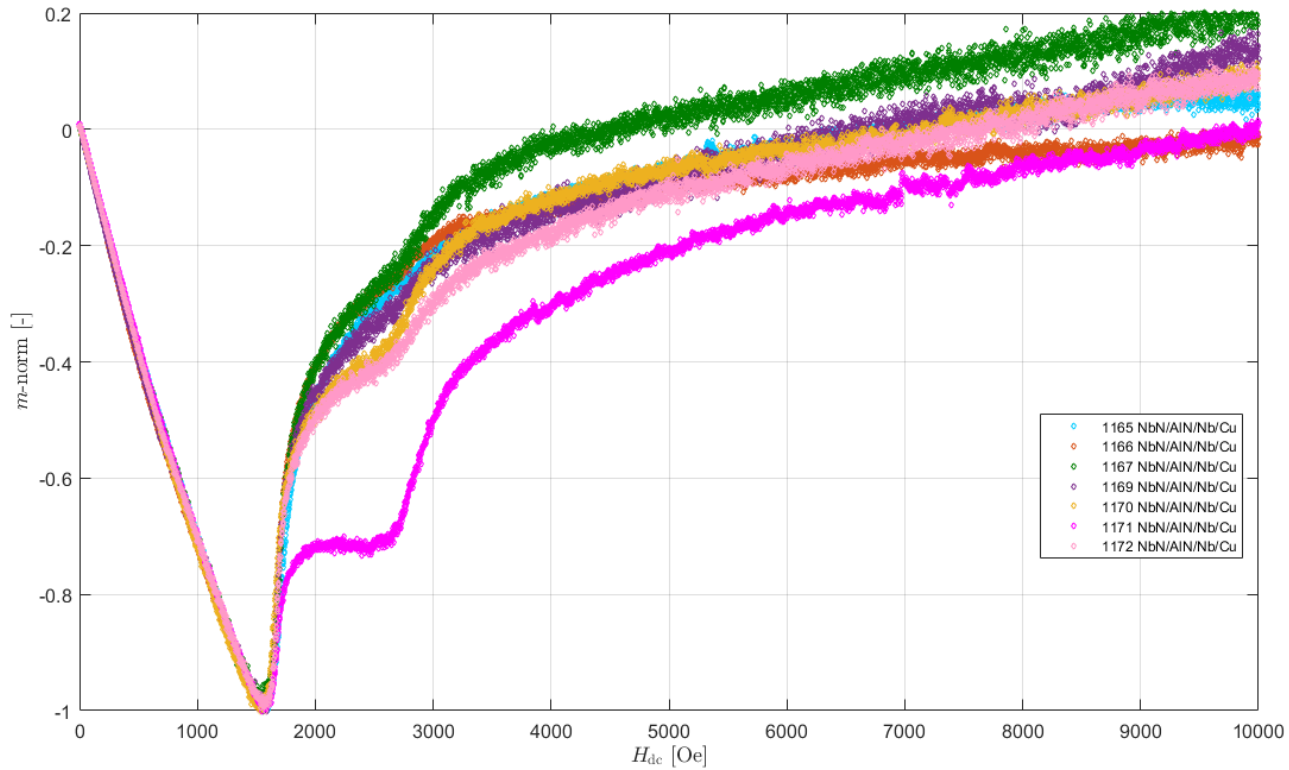
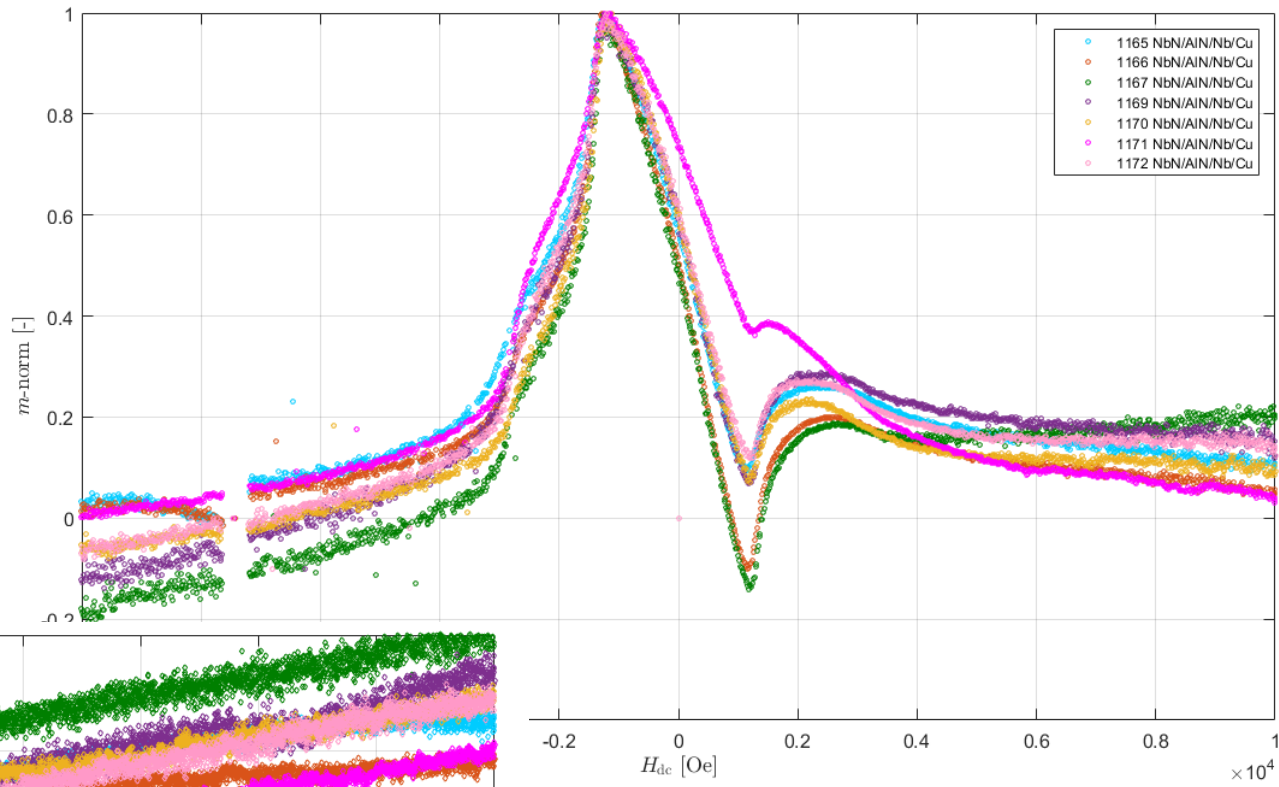
Siegen Uni

Nb / Cu



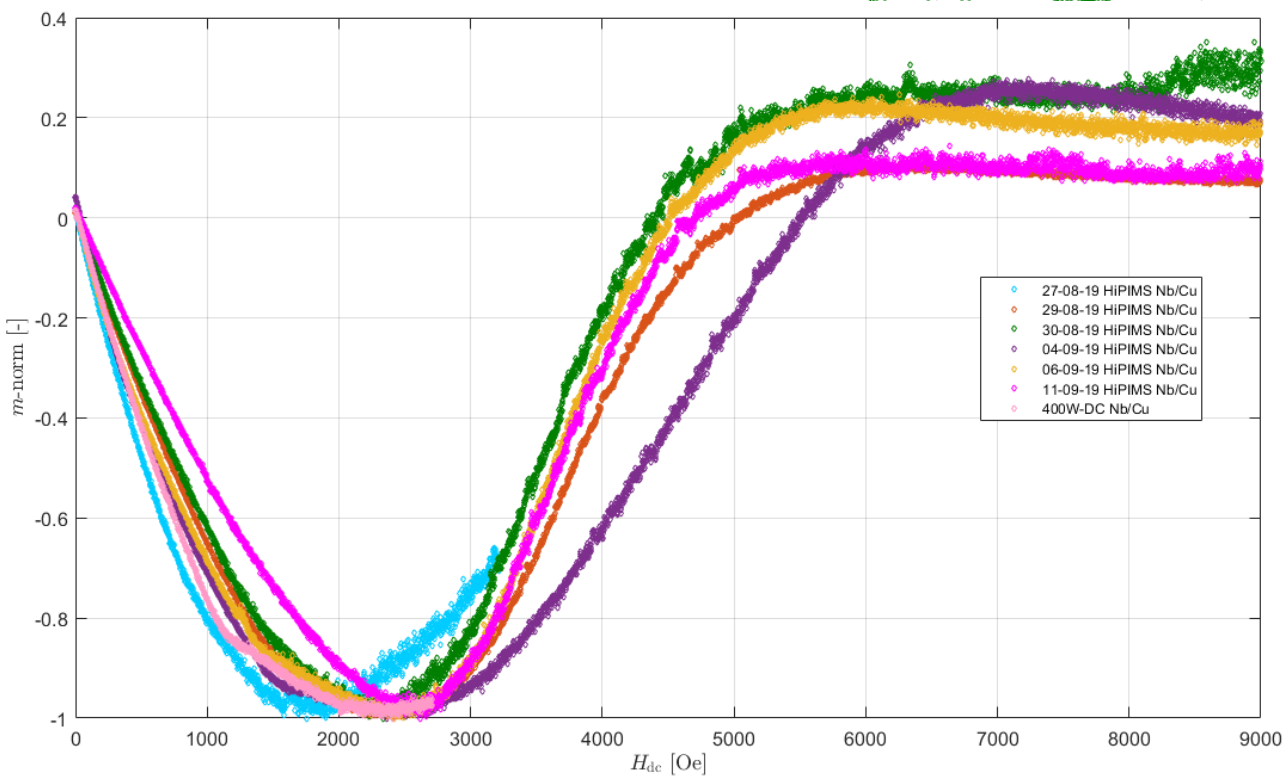
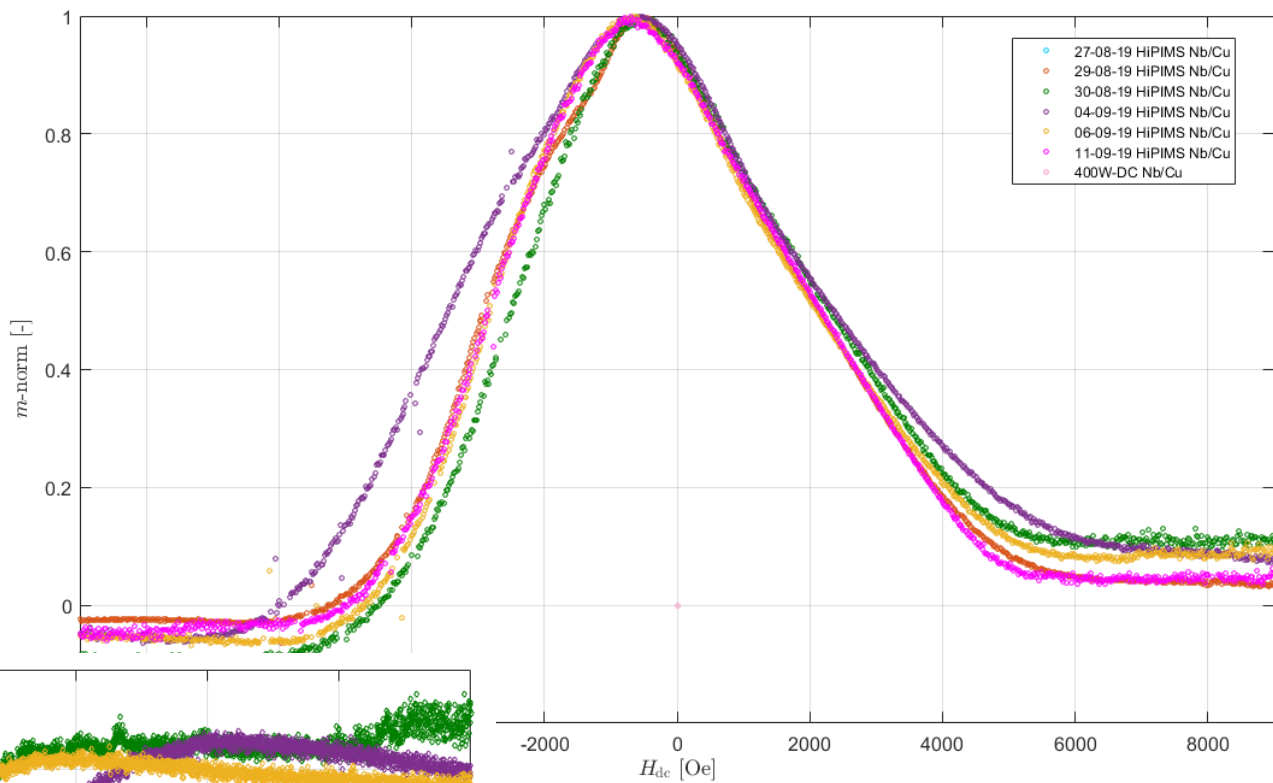
SIS 26.6.2020 series
Siegen Uni

NbN / AlN / Nb / Cu



HiPIMS Nb 22.7.2020 series STFC

Nb / Cu



HiPIMS Nb 4.9.2020 series

Siegen Uni

Nb / Cu

